Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/590,839	CHYUN, CHAN HYUK
Examiner	Art Unit
Honomin Fan	2612

SEARCHED				
Class	Subclass	Date	Examiner	
340	541	1/28/2008	HF	
	552-557			
	573.2			
	573.3			
	545:3	*	-	
	565-567			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
B. Lee D. Goins	1/28/2008	HF		
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